

Notic of References Cited

Application/Control No.

10/035,690

Applicant(s)/Patent Under
Reexamination
CHEN ET AL.

Examiner

DAVID VU

Art Unit

2818

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,103,456	08-2000	Tobben et al.	430/317
	B	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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